# MOSFET - Power, Single N-Channel 80 V, 1.1 m $\Omega$ , 335 A

#### **Features**

- Small Footprint (8x8 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb-Free and are RoHS Compliant

# MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	80	V
Gate-to-Source Voltage	9		V <sub>GS</sub>	±20	V
Continuous Drain	Steady	T <sub>C</sub> = 25°C	I <sub>D</sub>	335	Α
Current R <sub>θJC</sub> (Notes 1, 3)		T <sub>C</sub> = 100°C		237	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	300	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		150	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	41	Α
Current R <sub>θJA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		29	
Power Dissipation	State T <sub>A</sub> = 25°C		$P_{D}$	5	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		2.5	
Pulsed Drain Current	T <sub>A</sub> = 25	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Source Current (Body Diode)			Is	335	Α
Single Pulse Drain-to-Source Avalanche Energy (L = 3 mH, I <sub>L(pk)</sub> = 34 A)			E <sub>AS</sub>	1734	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.5	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	30	

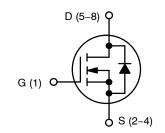
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



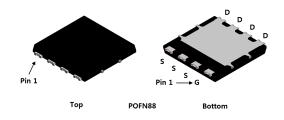
# ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)</sub>	DSS	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
80	٧	1.1 m $\Omega$ @ 10 V	335 A



**N-CHANNEL MOSFET** 



DFNW8 CASE 507AP

# **MARKING DIAGRAM**



A = Assembly Location
WL = 2-digit Wafer Lot Code

Y = Year Code WW = Work Week Code

#### **ORDERING INFORMATION**

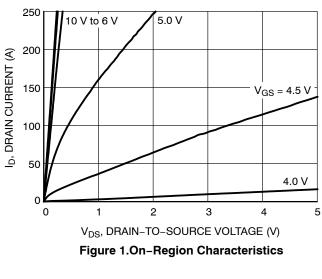
See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

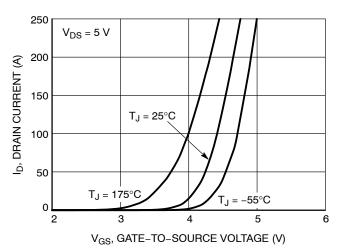
# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				57		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25 ^{\circ}\text{C}$				10	
		V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = I_{DS}$	= 590 μΑ	2.0	2.9	4.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-7.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 90 A		0.93	1.1	
		V <sub>GS</sub> = 6 V	I <sub>D</sub> = 59 A		1.28	1.6	mΩ
Forward Transconductance	9 <sub>F</sub> s	V <sub>DS</sub> =15 V, I <sub>D</sub>	= 90 A		400		S
CHARGES, CAPACITANCES & GATE RI	SISTANCE						•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 500 kHz, V <sub>DS</sub> = 40 V			10100		
Output Capacitance	Coss				1455		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				43		1
Total Gate Charge	Q <sub>G(TOT)</sub>				147		
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 64 V; I <sub>D</sub> = 90 A			27		nC
Gate-to-Source Charge	Q <sub>GS</sub>				41		
Gate-to-Drain Charge	$Q_GD$				32		
Plateau Voltage	$V_{GP}$				4		V
SWITCHING CHARACTERISTICS (Note	5)						
Turn-On Delay Time	t <sub>d(ON)</sub>				29		
Rise Time	t <sub>r</sub>	$V_{GS} = 10 \text{ V}, V_{DS}$	s = 64 V.		14		] _
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 90 \text{ A}, R_G = 2.5 \Omega$			66		- ns
Fall Time	t <sub>f</sub>				19		
DRAIN-SOURCE DIODE CHARACTERIS	STICS				<u> </u>		-
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.8	1.2	\ ,.
		$I_S = 90 \text{ A}$ $T_J = 10 \text{ A}$			0.6		V
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 90 A			84		ns
Reverse Recovery Charge	$Q_{RR}$				189		nC

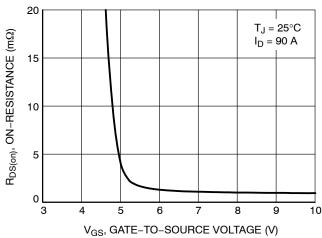
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ . 5. Switching characteristics are independent of operating junction temperatures.

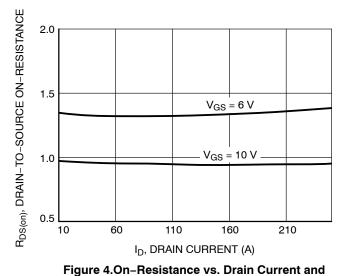
#### **TYPICAL CHARACTERISTICS**





**Figure 2.Transfer Characteristics** 





**Gate Voltage** 

Figure 3.On-Resistance vs. Gate-to-Source Voltage

2.6

2.4

2.2

2.0

1.6

1.4

1.2 1.0 8.0 V<sub>GS</sub> = 10 V

-25

-50

 $I_{D} = 90 \text{ A}$ 

R<sub>DS(on)</sub>, NORMALIZED DRAIN-TO-SOURCE ON-RESISTANCE

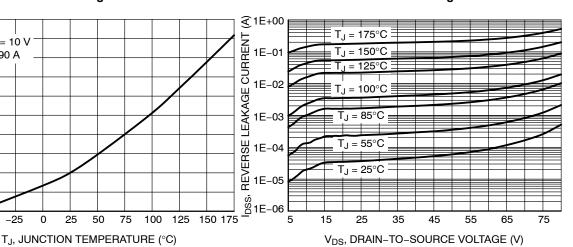


Figure 5.On-Resistance Variation with **Temperature** 

25

Figure 6.Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

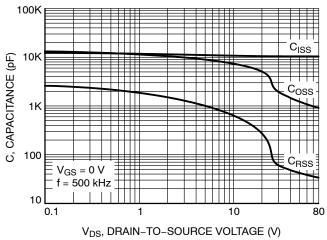


Figure 7. Capacitance Variation

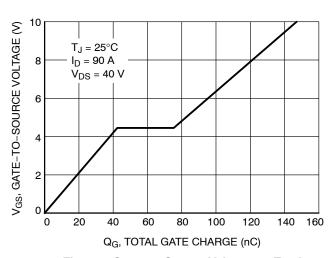


Figure 8.Gate-to-Source Voltage vs. Total Charge

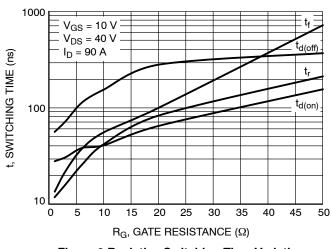


Figure 9.Resistive Switching Time Variation vs. Gate Resistance

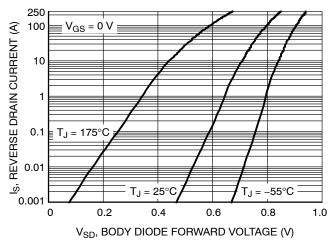


Figure 10.Diode Forward Voltage vs. Current

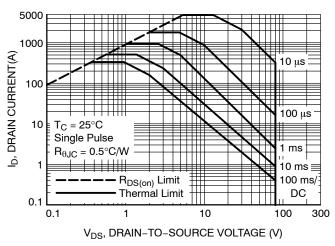


Figure 11.Maximum Rated Forward Biased Safe Operating Area

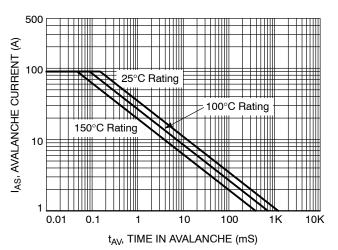


Figure 12.Maximum Drain Current vs. Time in Avalanche

# **TYPICAL CHARACTERISTICS**

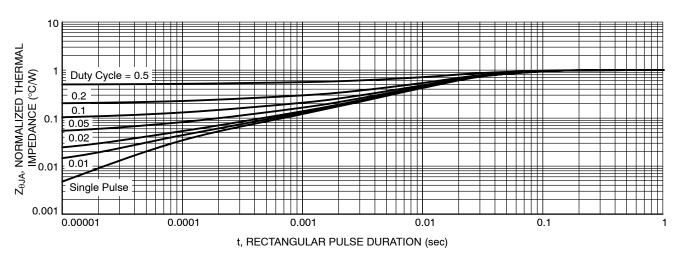


Figure 13. Transient Thermal Impedance

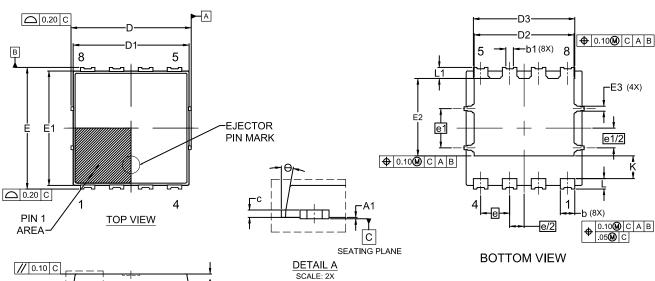
### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMTS1D2N08H	NTMTS1D2N08H	POWER 88 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

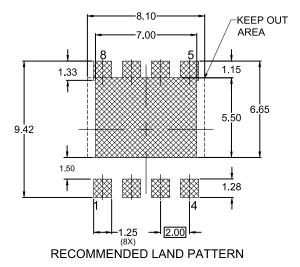
#### **PACKAGE DIMENSIONS**

#### DFNW8 8.3x8.4, 2P CASE 507AP ISSUE A





FRONT VIEW



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS.
- 4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
- SEATING PLANE IS DEFINED BY THE TERMINALS.

  "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

DIM	MILLIMETERS				
Diw	MIN.	NOM.	MAX.		
Α	1.00	1.10	1.20		
A1	0.00	-	0.05		
р	0.90	1.00	1.10		
b1	0.43	0.53	0.63		
С	0.23	0.28	0.33		
О	8.20	8.30	8.40		
D1	7.90	8.00	8.10		
D2	6.80	6.90	7.00		
D3	6.90	7.00	7.10		
Е	8.30	8.40	8.50		
E1	7.80	7.90	8.00		
E2	5.24	5.34	5.44		
E3	0.25	0.35	0.45		
е	2.00 BSC				
e/2	1.00 BSC				
e1	2.70 BSC				
e1/2	1.35 BSC				
K	1.50	1.57	1.70		
Г	0.64	0.74	0.84		
L1	0.67	0.77	0.87		
θ	0°		12°		

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